

TOSHIBA POWER MOS FET MODULE SILICON N CHANNEL MOS TYPE (L²-π-MOSⅣ 4 IN 1)

MP4703

HIGH POWER, HIGH SPEED SWITCHING APPLICATIONS.

HAMMER DRIVE, PULSE MOTOR DRIVE AND INDUCTIVE LOAD SWITCHING.

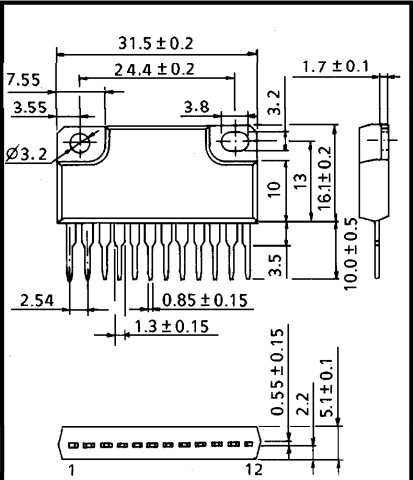
- 4-Volt Gate Drive
- Package with Heat Sink Isolated to Lead (SIP 12 Pin)
- High Drain Power Dissipation (4 Devices Operation)
: P_T=36W (T_c=25°C)
- Low Drain-Source ON Resistance : R_{DS (ON)}=0.20Ω (Typ.)
- Low Leakage Current : I_{GSS}=±10μA (Max.) (V_{GS}=±16V)
I_{DSS}=100μA (Max.) (V_{DS}=120V)
- Enhancement-Mode : V_{th}=0.8~2.0V (I_D=1mA)

MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Drain-Source Voltage	V _{DSS}	120	V
Gate-Source Voltage	V _{GSS}	±20	V
Drain Current	I _D	5	A
Peak Drain Current	I _{DP}	10	A
Drain Power Dissipation (1 Device Operation)	P _D	3.0	W
Drain Power Dissipation (4 Devices Operation)	P _{DT}	5.0	W
		36	
Channel Temperature	T _{ch}	150	°C
Storage Temperature Range	T _{stg}	-55~150	°C

INDUSTRIAL APPLICATIONS

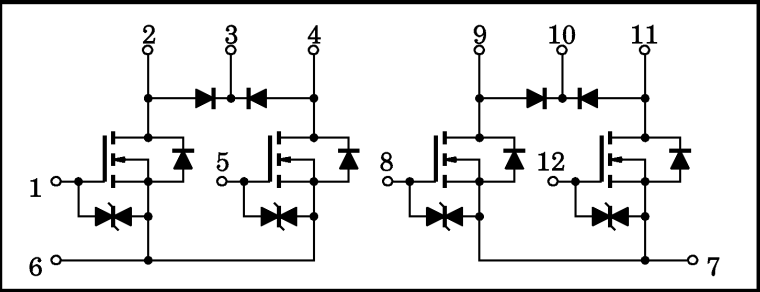
Unit in mm



MOST FET	DIODE
1, 5, 8, 12 GATE	2, 4, 9, 11
2, 4, 9, 11 DRAIN	ANODE
6, 7 SOURCE	3, 10 CATHODE
JEDEC	—
EIAJ	—
TOSHIBA	2-32B1G

Weight : 6.0g

ARRAY CONFIGURATION

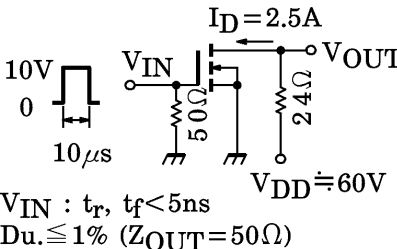


THERMAL CHARACTERISTICS

CHARACTERISTIC	SYMBOL	MAX.	UNIT
Thermal Resistance of Channel to Ambient (4 Devices Operation, $T_a = 25^\circ\text{C}$)	$\Sigma R_{th(ch-a)}$	25	$^\circ\text{C} / \text{W}$
Thermal Resistance of Channel to Case (4 Devices Operation, $T_c = 25^\circ\text{C}$)	$\Sigma R_{th(ch-c)}$	3.47	$^\circ\text{C} / \text{W}$
Maximum Lead Temperature for Soldering Purposes (3.2mm from Case for 10s)	T_L	260	$^\circ\text{C}$

This Transistor is an Electrostatic Sensitive Device. Please Handle with Caution.

ELECTRICAL CHARACTERISTICS ($T_a = 25^\circ\text{C}$)

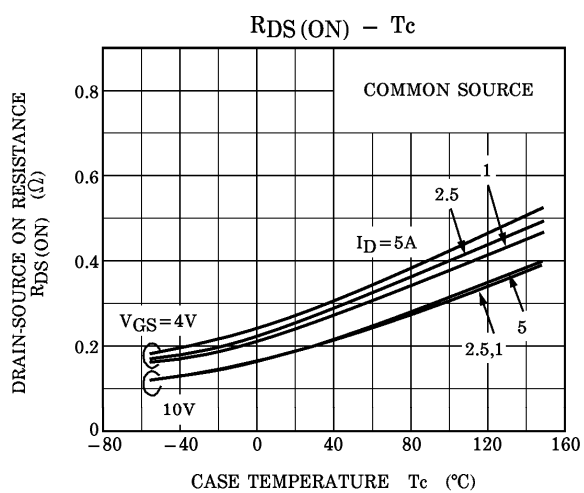
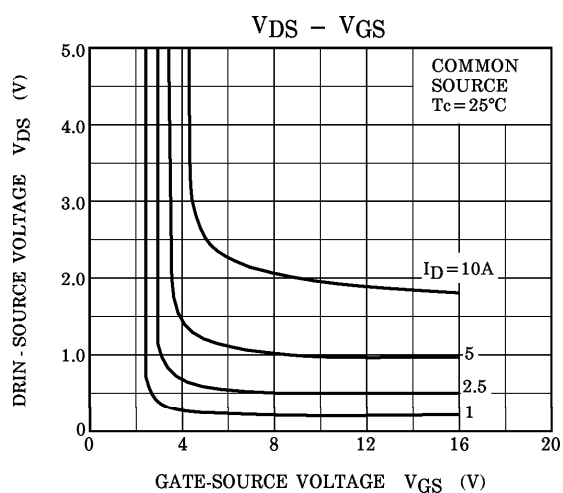
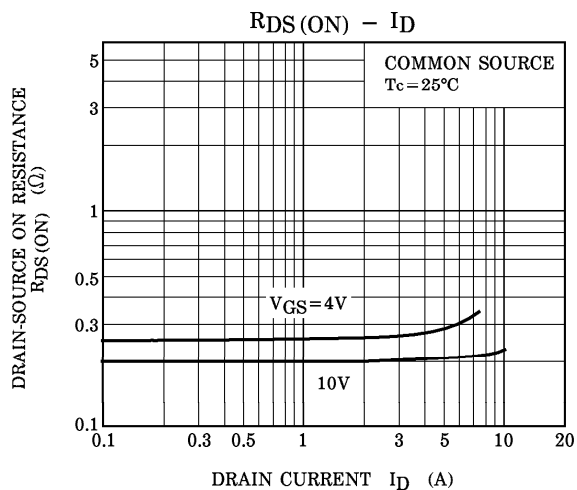
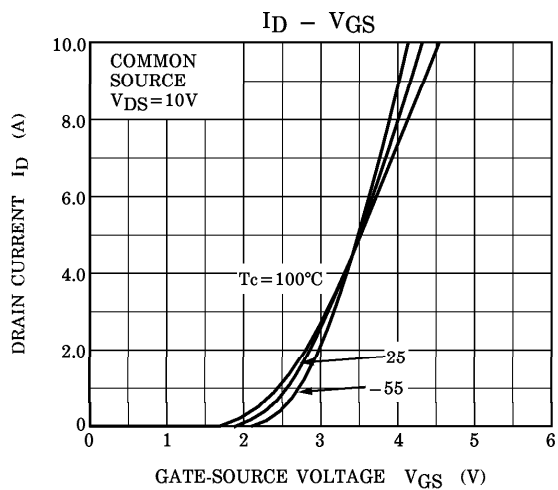
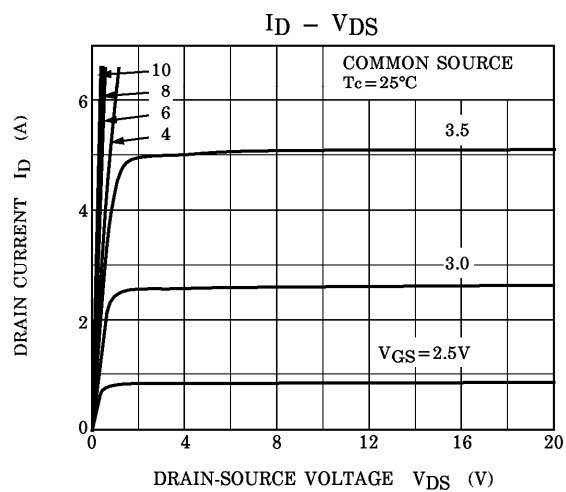
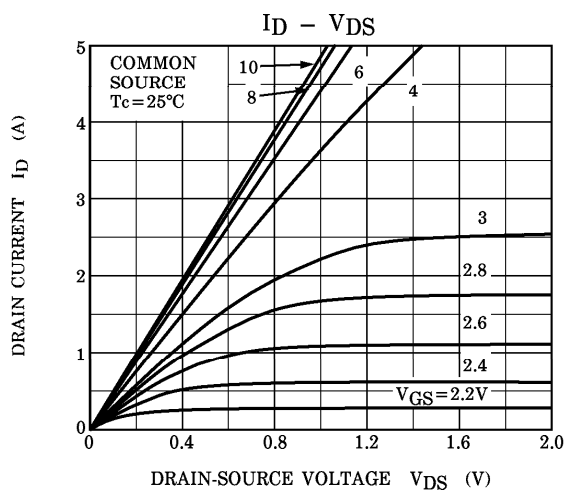
CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Gate Leakage Current		I _{GSS}	V _{GS} = ±16V, V _{DS} = 0	—	—	±10	μA
Drain Cut-off Current		I _{DSS}	V _{DS} = 120V, V _{GS} = 0	—	—	100	μA
Drain-Source Breakdown Voltage		V (BR) DSS	I _D = 10mA, V _{GS} = 0	120	—	—	V
Gate Threshold Voltage		V _{th}	V _{DS} = 10V, I _D = 1mA	0.8	—	2.0	V
Forward Transfer Admittance		Y _{fs}	V _{DS} = 10V, I _D = 2.5A	2.0	4.0	—	S
Drain-Source ON Resistance		R _{DS (ON)}	I _D = 2.5A, V _{GS} = 4V	—	0.28	0.44	Ω
		R _{DS (ON)}	I _D = 2.5A, V _{GS} = 10V	—	0.20	0.30	
Input Capacitance		C _{iss}	V _{DS} = 10V, V _{GS} = 0, f = 1MHz	—	540	—	pF
Reverse Transfer Capacitance		C _{rss}		—	47	—	
Output Capacitance		C _{oss}		—	180	—	
Switching Time	Rise Time	t _r	 I_D = 2.5A V_{IN} V_{OUT} 10V 0 10μs 50Ω 24Ω V_{DD} ≐ 60V V_{IN} : t_r, t_f < 5ns Du. ≤ 1% (Z_{OUT} = 50Ω)	—	15	—	ns
	Turn-on Time	t _{on}		—	50	—	
	Fall Time	t _f		—	40	—	
	Turn-off Time	t _{off}		—	280	—	
Total Gate Charge (Gate-Source Plus Gate-Drain)		Q _g	I _D = 5A, V _{GS} = 10V, V _{DD} = 96V	—	27	—	nC
Gate-Source Charge		Q _{gs}		—	18	—	
Gate-Drain (“Miller”) Charge		Q _{gd}		—	9	—	

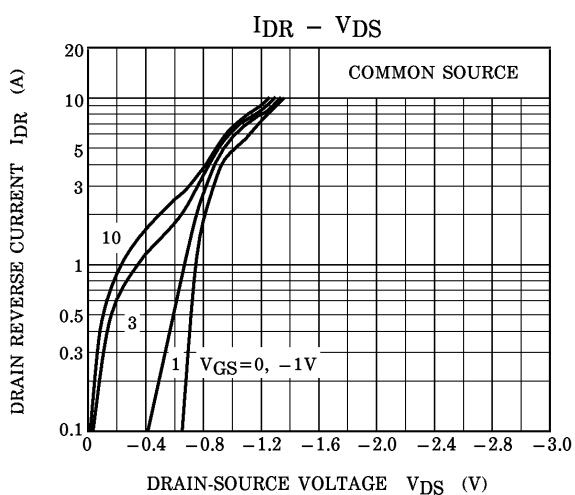
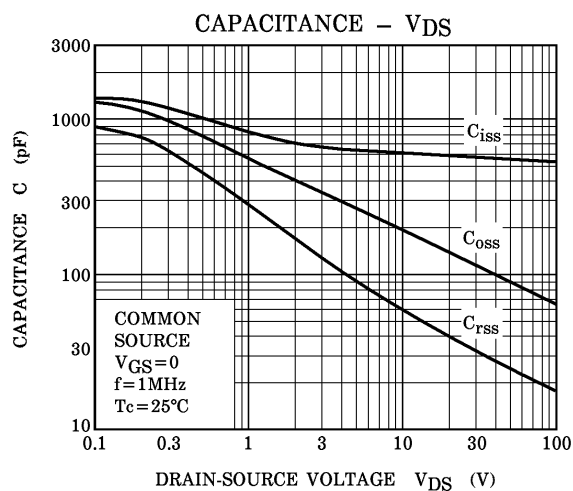
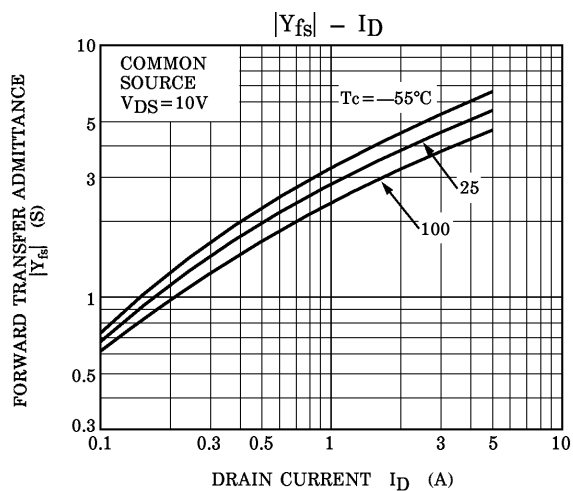
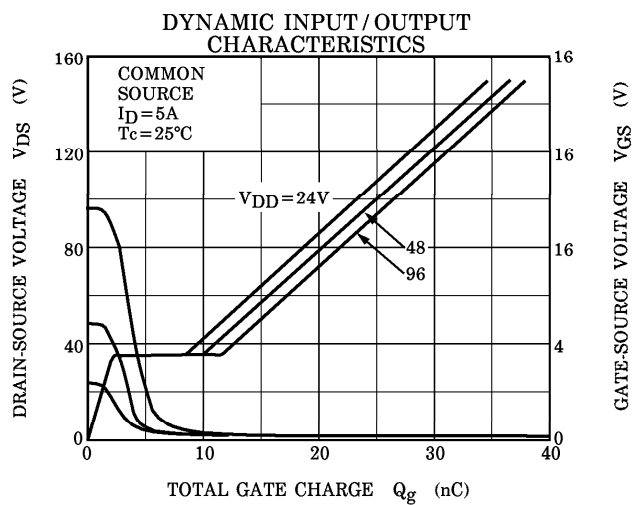
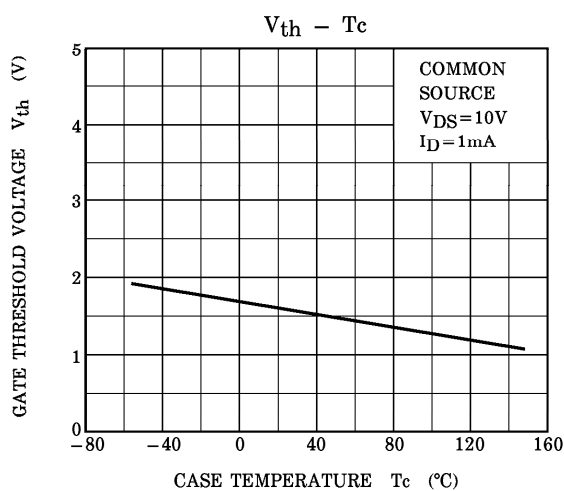
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (Ta = 25°C)

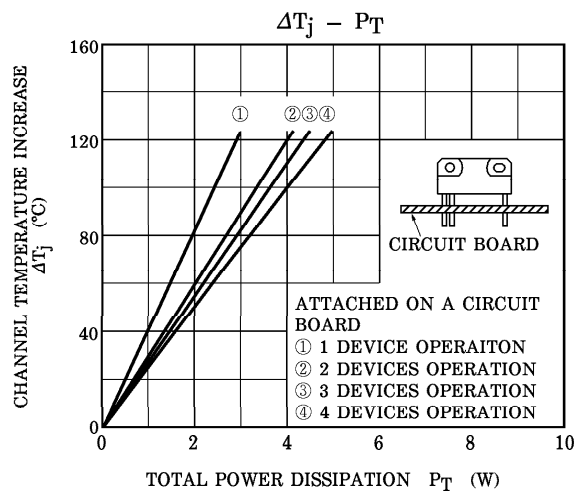
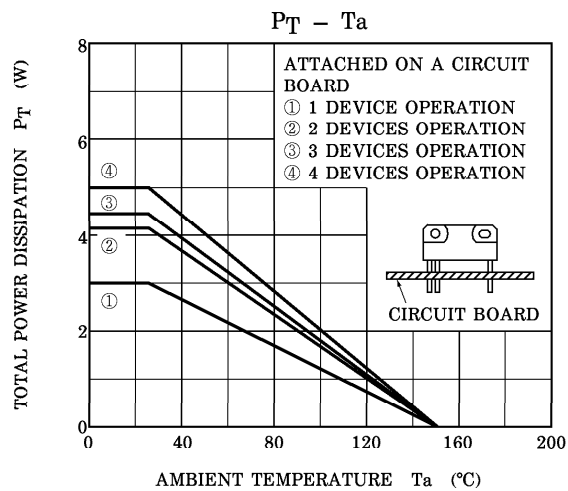
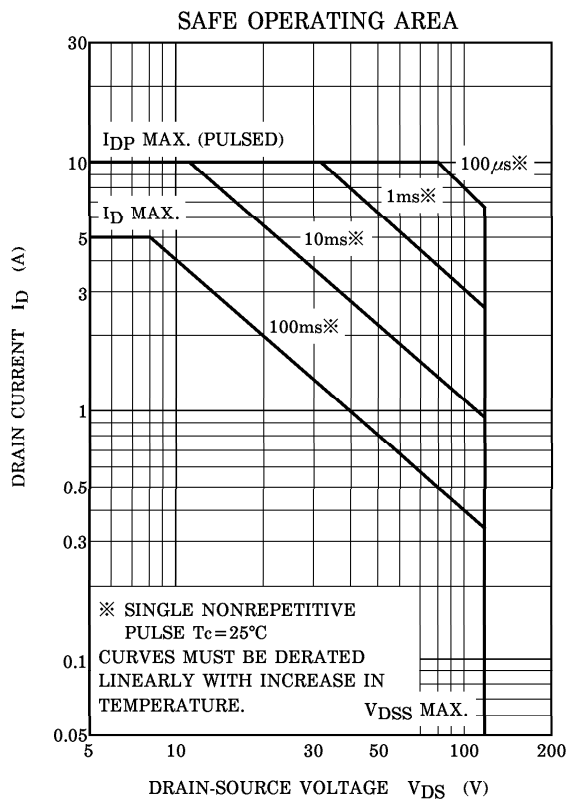
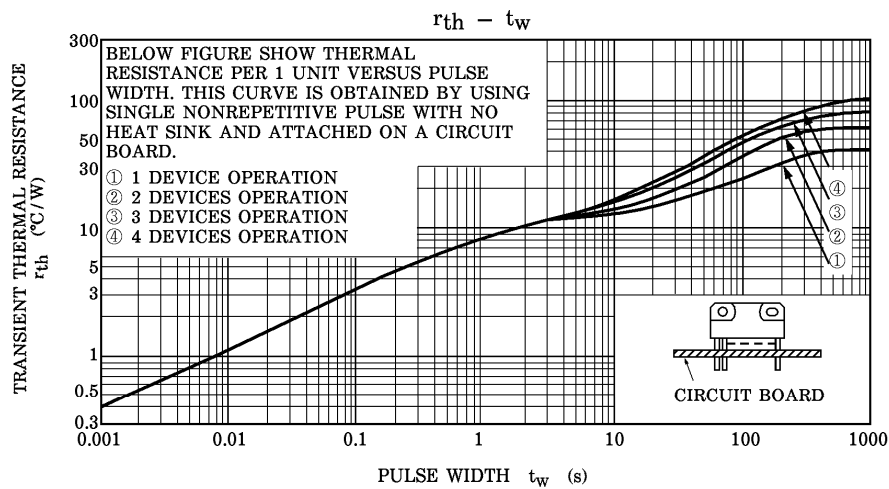
CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Drain Reverse Current	I_{DR}	—	—	—	5	A
Peak Drain Reverse Current	I_{DRP}	—	—	—	10	A
Diode Forward Voltage	V_{DSF}	$I_{DR}=5A, V_{GS}=0$	—	−1.0	−1.5	V
Reverse Recovery Time	t_{rr}	$I_{DR}=5A, V_{GS}=0$ $dI_{DR}/dt = -50A/\mu s$	—	180	—	ns
Reverse Recovery Charge	Q_{rr}		—	0.54	—	μC

FLYBACK-DIODE RATINGS CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Forward Current	I_{FM}	—	—	—	5	A
Reverse Current	I_R	$V_R=120V$	—	—	0.4	μA
Reverse Voltage	V_R	$I_R=100\mu A$	120	—	—	V
Forward Voltage	V_F	$I_F=2A$	—	—	2.3	V







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